

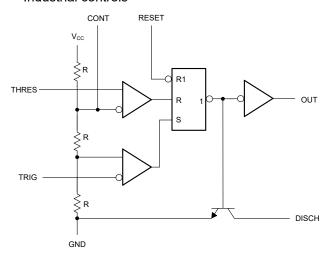
Nx556, Sx556 Dual Precision Timers

1 Features

- Two precision timing circuits per package
- Astable or monostable operation
- TTL-compatible output can sink or source up to 200mA
- Active pullup or pulldown

2 Applications

- Precision timers from microseconds to hours
- Pulse-shaping circuits
- Missing-pulse detectors
- Pulse-width modulators
- Pulse-position modulators
- Sequential timers
- Pulse generators
- Frequency dividers
- Application timers
- Industrial controls



Simplified Schematic (Each Timer)

3 Description

The Nx556 and Sx556 devices provide two independent timing circuits of the NA555, NE555, SA555, or SE555 type in each package. These circuits operate in an astable or monostable mode with external resistor-capacitor (RC) timing control. The basic timing provided by the RC time constant is controlled actively by modulating the bias of the control-voltage input.

Each timer has a trigger level equal to approximately one-third of the supply voltage and a threshold level equal to approximately two-thirds of the supply voltage. These levels can be altered by use of the control voltage pin (CONT). When the trigger input (TRIG) is less than the trigger level, the flip-flop is set and the output goes high. If TRIG is greater than the trigger level and the threshold input (THRES) is greater than the threshold level, the flip-flop is reset and the output is low. The reset input (RESET) overrides all other inputs and is used to initiate a new timing cycle. If RESET is low, the flip-flop is reset and the output is low. Whenever the output is low, a lowimpedance path is provided between the discharge pin (DISCH) and the ground pin (GND). Tie all unused inputs to an appropriate logic level to prevent false triggering.

Device Information

Device information							
PART NUMBER	OPERATING TEMPERATURE	PACKAGE ⁽¹⁾					
NA556	$T_{\Delta} = -40^{\circ}\text{C to } +105^{\circ}\text{C}$	D (SOIC, 14)					
	1A = -40 C to +103 C	N (PDIP, 14)					
		D (SOIC, 14)					
NE556	T _Δ = 0°C to 70°C	DB (SSOP, 14)					
INESSO	1A - 0 C to 70 C	N (PDIP, 14)					
		NS (SO, 14)					
SA556	$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$	N (PDIP, 14)					
SE556	$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$	J (CDIP, 14)					

For more information, see Section 10.



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4 Pin Configuration and Functions

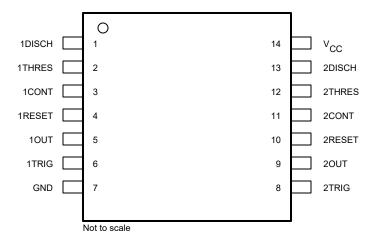


Figure 4-1. NA556: D, 14-Pin SOIC, and N, 14-Pin PDIP
NE556: D, 14-Pin SOIC, DB, 14-Pin SSOP, N, 14-Pin PDIP, and NS, 14-Pin SO
SA556: N, 14-Pin PDIP
SE556: J, 14-Pin CDIP
(Top View)

Table 4-1. Pin Functions

	PIN	TYPE	DESCRIPTION	
NAME	NAME NO.		DESCRIPTION	
CONT	3, 11	Input	Controls comparator thresholds. Outputs 2/3 V_{CC} and allows bypass capacitor connection.	
DISCH	1, 13	Output	Open collector output to discharge timing capacitor.	
GND	7	_	Ground.	
OUT	5, 9	Output	High current timer output signal.	
RESET	4, 10	Input	Active low reset input forces output and discharge low.	
THRES	2, 12	Input	End of timing input. THRES > CONT sets output low and discharge low.	
TRIG	6, 8	Input	Start of timing input. TRIG < 1/2 CONT sets output high and discharge open.	
V _{CC}	14	_	Power-supply voltage.	



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage ⁽²⁾			18	V
VI	Input voltage: CONT, RESET, THRES, and TRIG			Vcc	V
Io	Output current			±225	mA
T _J	Operating virtual junction temperature			150	°C
	Load temporature 1 6mm (1/16 inch) from 2000	J package, 60 seconds		300	°C
	Lead temperature 1.6mm (1/16 inch) from case D, N, or NS package, 10 seconds			260	
T _{stg}	Storage temperature	·	-65	150	°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±500	V
V _(ESD) Electro	Liectrostatic discharge	Charged device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1500	V

⁽¹⁾ JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

			MIN	MAX	UNIT
V	Supply voltage	NA556, NE556, SA556	4.5	16	V
V _{CC}		SE556	4.5	18	v
Io	I _O Output current			±200	mA
		NA556	-40	105	
_	Operating free-air temperature	NE556	0	70	°C
T _A		SA556	-40	85	
		SE556	– 55	125	

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		NA556, NE556	NE556	SE556	NA556, NE556, SA556	NE556	
		D (SOIC)	DB (SSOP)	J (CDIP)	N (PDIP)	NS (SOP)	UNIT
		14 PINS	14 PINS	14 PINS	14 PINS	14 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	91.4	104.5	86.1	73.4	89.5	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	51.7	56.3	38.8	51.7	47.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	49.6	64.1	73.5	47.6	52.9	°C/W
ΨЈТ	Junction-to-top characterization parameter	12.3	14.0	32.4	29.5	11.3	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	49.1	63.3	68.7	47.0	52.3	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	20.1	N/A	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

⁽²⁾ All voltage values are with respect to network ground terminal.

⁽²⁾ JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.



5.5 Electrical Characteristics

at V_{CC} = 5V to 15V and T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITION	IS	MIN	TYP	MAX	UNIT
		V _{CC} = 15V	NA556, NE556, SA556	8.8	10	11.2	
	Thursday and scales are lessed		SE556	9.4	10	10.6	V
V _T	Threshold voltage level	V _{CC} = 5V	NA556, NE556, SA556	2.4	3.3	4.2	V
			SE556	2.7	3.3	4	
I _T	Threshold current ⁽¹⁾				30	250	nA
		V _{CC} = 15V	NA556, NE556, SA556	4.5	5	5.6	
			SE556	4.8	5	5.2	
\ /	Trigger veltege level	V _{CC} = 15V, T _A = -55°C to +125°C	SE556	3		6	V
V_{TRIG}	Trigger voltage level	V _{CC} = 5V	NA556, NE556, SA556	1.1	1.67	2.2	V
			SE556	1.45	1.67	1.9	
		$V_{CC} = 5V$, $T_A = -55^{\circ}C$ to +125°C	SE556			1.9	
I _{TRIG}	Trigger current	V _{TRIG} = 0V	NA556, NE556, SA556		0.5	2	μΑ
			SE556		0.5	0.9	
V	Reset voltage level			0.3	0.7	1	V
V _{RESET}	Reset voltage level	T _A = -55°C to +125°C	SE556			1.1	V
		V _{RESET} = V _{CC}			0.1	0.4	
I _{RESET}	Reset current	V _{RESET} = 0V	NA556, NE556, SA556		-0.4	1.5	mA
			SE556		-0.4	-1	
I _{DISCH}	Discharge switch off-state current				20	100	nA
		V _{CC} = 15V	NA556, NE556, SA556	9	10	11	
			SE556	9.6	10	10.4	
	Control voltage	V _{CC} = 15V, T _A = -55°C to +125°C	SE556	9.6		10.4	V
V _{CONT}	(open circuit)	V _{CC} = 5V	NA556, NE556, SA556	2.6	3.3	4	V
			SE556	2.9	3.3	3.8]
		V_{CC} = 5V, T_A = -55°C to +125°C	SE556	2.9		3.8	



5.5 Electrical Characteristics (continued)

at V_{CC} = 5V to 15V and T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDIT	TIONS	MIN	TYP	MAX	UNIT
		V _{CC} = 15V, I _{OL} = 10mA	NA556, NE556, SA556		0.1	0.25	
		00 02	SE556		0.1	0.15	
		V_{CC} = 15V, I_{OL} = 10mA, T_A = -55°C to +125°C	SE556			0.2	
		V _{CC} = 15V, I _{OL} = 50mA	NA556, NE556, SA556		0.4	0.75	
			SE556		0.4	0.5	
		$V_{CC} = 15V$, $I_{OL} = 50$ mA, $T_A = -55$ °C to +125°C	SE556			1	
		V _{CC} = 15V, I _{OL} = 100mA	NA556, NE556, SA556		2	2.5	
	Low-level	00 1 7 02 11 11	SE556		2	2.2	
V _{OL}	output voltage	V_{CC} = 15V, I_{OL} = 100mA, T_A = -55°C to +125°C	SE556			2.7	V
		V _{CC} = 15V, I _{OL} = 200mA	V _{CC} = 15V, I _{OL} = 200mA		2.5		
		$V_{CC} = 5V$, $I_{OL} = 3.5$ mA, $T_A = -55$ °C to +125°C	SE556			0.35	
		V _{CC} = 5V, I _{OL} = 5mA	NA556, NE556, SA556		0.1	0.25	
			SE556		0.1	0.15	
		$V_{CC} = 5V, I_{OL} = 5mA,$ $T_A = -55^{\circ}C \text{ to } +125^{\circ}C$	SE556			0.8	
		V _{CC} = 5V, I _{OL} = 8mA	NA556, NE556, SA556		0.15	0.3	
		35 1 32	SE556		0.15	0.25	
		V _{CC} = 15V, I _{OH} = -100mA	NA556, NE556, SA556	12.75	13.3		
		3.1	SE556	13	13.3		
		$V_{CC} = 15V$, $I_{OH} = -100$ mA, $T_A = -55$ °C to +125°C	SE555	12			
V _{OH}	High-level output voltage	V _{CC} = 15V, I _{OH} = -200mA	'		12.5		V
	output voltage	V _{CC} = 5V, I _{OH} = -100mA	NA556, NE556, SA556	2.75	3.3		
			SE556	3	3.3		
		$V_{CC} = 5V, I_{OH} = -100mA,$ $T_A = -55^{\circ}C \text{ to } +125^{\circ}C$	SE555	2			

5.5 Electrical Characteristics (continued)

at V_{CC} = 5V to 15V and T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
		Output low, no load, V _{CC} = 15V	NA556, NE556, SA556		20	30	
			SE556		20	24	
	Supply current	Output low, no load, V _{CC} = 5V	NA556, NE556, SA556		6	12	
			SE556		6	10	mA
Icc		Output high, no load, V _{CC} = 15V	NA556, NE556, SA556		18	26	IIIA
			SE556		18	20	
		Output high, no load, V _{CC} = 5V	NA556, NE556, SA556		4	10	
			SE556		4	8	

⁽¹⁾ This parameter influences the maximum value of the timing resistors R_A and R_B in the circuit of Figure 6-3. For example, when V_{CC} = 5V, the maximum value is R_A + R_B \cong 3.4M Ω , and for V_{CC} = 15V, the maximum value is R_A + R_B \cong 10M Ω .

5.6 Switching Characteristics

 V_{CC} = 5V and 15V, T_A = 25°C (unless otherwise noted); characteristic values are specified by design, characterization, or both, and are not production tested

	PARAMETER	TEST CON	DITIONS ⁽¹⁾	MIN 7	ГΥР	MAX	UNIT
		Each timer, monostable ⁽²⁾ ,	NA556, NE556, SA556		50		
		$T_A = MIN \text{ to } MAX$	SE556		30	100	
	Temperature coefficient of timing interval	Each timer, astable ⁽³⁾ ,	NA556, NE556, SA556		150		ppm/°C
		$T_A = MIN \text{ to MAX}$	SE556		90		
		Timer 1 – Timer 2, T _A =	MIN to MAX		±10		
	Supply voltage sensitivity of timing	Each timer, monostable ⁽²⁾	NA556, NE556, SA556		0.1	0.5	
		monostable (=)	SE556	().05	0.2	
		nsitivity of timing Each timer, astable ⁽³⁾	NA556, NE556, SA556		0.3		%/V
	interval		SE556	().15		
		Timer 1 – Timer 2	NA556, NE556, SA556	4	:0.2		
			SE556	±	:0.1		
t _r	Output pulse rise time	C _L = 15pF, T _A = 25°C, 20% to 80%	NA556, NE556, SA556		100	300	ns
	20% to 8	20% 10 00%	SE556		100	200	
t _f	Output pulse fall time	C _L = 15pF, T _A = 25°C, 80% to 20%	NA556, NE556, SA556	56,	100	300	ns
			SE556		100	200	

- (1) For conditions shown as MIN or MAX, use the appropriate value specified under Recommended Operating Conditions.
- (2) Values specified are for a device in a monostable circuit similar to Figure 6-2, with the following component values: R_A = 2kΩ to 100kΩ, C_T = 0.1μF.
- (3) Values specified are for a device in an astable circuit similar to Figure 6-3, with the following component values: $R_A = 1k\Omega$ to $100k\Omega$, $C_T = 0.1\mu F$.



6 Detailed Description

6.1 Overview

The Nx556 or Sx556 is a precision timing device used for general-purpose timing applications. In the time-delay or monostable mode of operation, the timed interval is controlled by a single external resistor and capacitor network. In the astable mode of operation, the frequency and duty cycle can be controlled independently with two external resistors and a single external capacitor. RESET overrides TRIG, which overrides THRES (when CONT pin is $2/3 \, V_{CC}$).

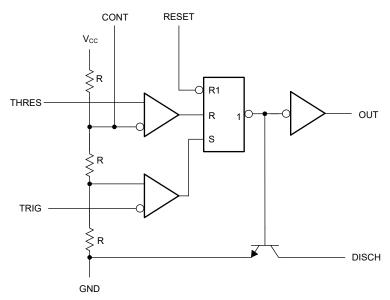
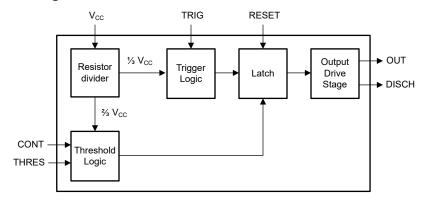


Figure 6-1. Simplified Schematic

6.2 Functional Block Diagram



6.3 Feature Description

6.3.1 Monostable Operation

For monostable operation, Figure 6-2 shows how either of the timers can be connected. If the output is low, application of a negative-going pulse to the trigger (TRIG) sets the internal latch; the output goes high, and discharge pin (DISCH) becomes open drain. Capacitor C_T then is charged through R_A until the voltage across the capacitor reaches the threshold voltage of the threshold (THRES) input. If TRIG has returned to a high level, the output of the threshold comparator resets the internal latch, the output goes low, the discharge pin goes low, which quickly discharges capacitor C_T .

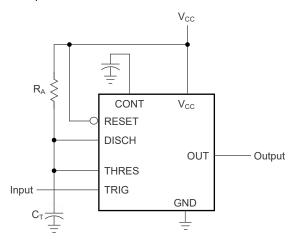


Figure 6-2. Circuit for Monostable Operation

Monostable operation is initiated when TRIG voltage is less than the trigger threshold. If initiated, the sequence ends only if TRIG is high for at least 10 μ s before the end of the timing interval. When the trigger is grounded, the comparator storage time can be as long as 10 μ s, which limits the minimum monostable pulse duration to 10 μ s. The output pulse duration is approximately $t_w = 1.1 \times R_A C_T$. The threshold levels and charge rates both are directly proportional to the supply voltage, V_{CC} . The timing interval is, therefore, independent of the supply voltage, so long as the supply voltage is constant during the time interval. In monostable applications, set the trip point of the trigger input by a voltage applied to CONT.

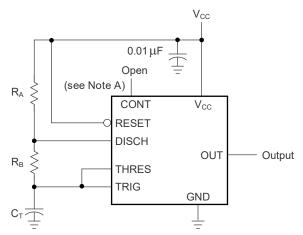
Applying a negative-going trigger pulse simultaneously to RESET and TRIG during the timing interval discharges capacitor C_T and reinitiates the cycle, commencing on the positive edge of the reset pulse. The output is held low as long as the reset pulse is low. To prevent false triggering, when RESET is not asserted low, connect RESET to V_{CC} . If the RESET function is required and the pin is driven by external logic or a microcontroller, use a pullup resistor to V_{CC} (such as $10k\Omega$) to prevent the RESET pin from floating. If the RESET function is not required, short the RESET pin directly to the V_{CC} pin.

6.3.2 Astable Operation

As shown in Figure 6-3, adding a second resistor, R_B , to the circuit of Figure 6-2 and connecting the trigger input to the threshold input causes the timer to self-trigger and run as a multivibrator. The capacitor C_T charges through R_B and R_B and then discharges through R_B only. Therefore, the duty cycle is controlled by the values of R_A and R_B .

This astable connection results in capacitor C_T charging and discharging between the threshold-voltage level ($\cong 0.67 \times V_{CC}$) and the trigger-voltage level ($\cong 0.33 \times V_{CC}$). As in the monostable circuit, charge and discharge times (and, therefore, the frequency and duty cycle) are independent of the supply voltage. To reduce distortion, use at maximum frequency of 100kHz or below. If higher-frequency operation is required, consider using the TLC556 LinCMOSTM Timer instead.





Decouple CONT voltage to ground with a capacitor to improve operation. Reevaluate for individual applications.

Figure 6-3. Circuit for Astable Operation

$$t_{\rm H} \cong 0.693 \times (R_{\rm A} + R_{\rm B}) \times C_{\rm T} \tag{1}$$

$$t_{L} \cong 0.693 \times R_{B} \times C_{T} \tag{2}$$

Other useful relationships for period, frequency, and driver-referred and waveform-referred duty cycle are shown as follows:

$$T = t_H + t_L \approx 0.693 \times (R_A + 2R_B) \times C_T \tag{3}$$

$$f = \frac{1}{T} \cong \frac{1.44}{(R_A + 2R_B) \times C_T}$$
 (4)

Output driver duty cycle =
$$\frac{t_L}{T} \cong \frac{R_B}{R_A + 2R_B}$$
 (5)

Output waveform duty cycle =
$$\frac{t_H}{T} \cong 1 - \frac{R_B}{R_A + 2R_B} = \frac{R_A + R_B}{R_A + 2R_B}$$
 (6)

6.4 Device Functional Modes

Table 6-1 shows the device truth table. For a valid reset voltage condition, use an external pullup resistor to V_{CC} (if using the RESET functionality), or short the RESET pin directly to V_{CC} (if the RESET functionality is not used).

Table 6-1. Function Table

RESET VOLTAGE(1)	TRIGGER VOLTAGE(1)	THRESHOLD VOLTAGE(1)	OUTPUT	DISCHARGE SWITCH	
LOW	Irrelevant	Irrelevant	Low	On	
> MAX	< 1/3 × V _{CC}	Irrelevant ⁽²⁾	High	Off	
> MAX	> 1/3 × V _{CC}	> 2/3 × V _{CC}	Low	On	
> MAX	> 1/3 × V _{CC}	< 2/3 × V _{CC}	As previously established		

- (1) Voltage levels shown are nominal.
- (2) CONT pin open or $2/3 \times V_{CC}$.

7 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

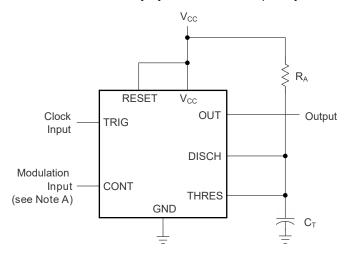
7.1 Application Information

The Nx556 and Sx556 timer devices use resistor and capacitor charging delay to provide a programmable time delay or operating frequency. The following sections present a simplified discussion of the design process. Reset mode forces output and discharge low and provides a small reduction in supply current.

7.2 Typical Applications

7.2.1 Pulse-Width Modulation

To modify timer operation, apply an external voltage (or current) to CONT to modulate the internal threshold and trigger voltages. Figure 7-1 shows a circuit for pulse-width modulation. A continuous input pulse train triggers the monostable circuit, and a control signal modulates the threshold voltage. Figure 7-2 shows the resulting duty cycle versus control voltage transfer function. Attempting to run under 10% duty cycle can result in inconsistent output pulses. Attempting to run close to 100% duty cycle results in frequency division by 2, then 3, then 4.



A. The modulating signal can be direct or capacitively coupled to CONT. For direct coupling, consider the effects of modulation source voltage and impedance on the bias of the timer.

Figure 7-1. Circuit for Pulse-Width Modulation

7.2.1.1 Design Requirements

The clock input must have V_{OL} and V_{OH} levels that are less than and greater than 1/3 V_{CC} , respectively. Clock input V_{OL} time must be less than minimum output high time; therefore, a high (positive) duty cycle clock is recommended. Minimum recommended modulation voltage is 1V. Lower CONT voltage can greatly increase threshold comparator propagation delay and storage time. The application must be tolerant of a nonlinear transfer function; the relationship between modulation input and pulse width is not linear because the capacitor charge is RC-based with an negative exponential curve.

7.2.1.2 Detailed Design Procedure

Choose R_A and C_T so that $R_A \times C_T$ is same or less than clock input period. Figure 7-2 shows the non linear relationship between control voltage and output duty cycle. Duty cycle is function of control voltage and clock period relative to RC time constant.



7.2.1.3 Application Curve

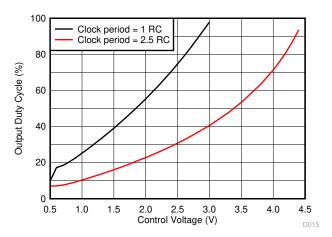
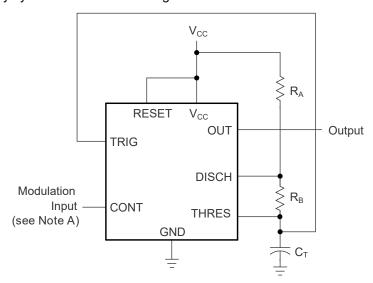


Figure 7-2. Pulse-Width-Modulation vs Control Voltage Clock Duty Cycle 98%, V_{CC} = 5V

7.2.2 Pulse-Position Modulation

Figure 7-3 shows that any of these timers can be used as a pulse-position modulator. This application modulates the threshold voltage, and thereby, the time delay of a free-running oscillator. Figure 7-4 and Figure 7-5 show the output frequency and duty cycle versus control voltage.



A. The modulating signal can be direct or capacitively coupled to CONT. For direct coupling, consider the effects of modulation source voltage and impedance on the bias of the timer.

Figure 7-3. Circuit for Pulse-Position Modulation

7.2.2.1 Design Requirements

Both dc- and ac-coupled modulation input changes the upper and lower voltage thresholds for the timing capacitor. Both frequency and duty cycle vary with the modulation voltage. Control voltage less than 1V can result in output glitches instead of a steady-output pulse stream. Table 7-1 gives example design requirements.

Table 7-1. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
R _A	3kΩ
R _B	309Ω
C _T	1nF

7.2.2.2 Detailed Design Procedure

The nominal output frequency and duty cycle for control voltage set to 2/3 of V_{CC} can be determined using formulas in Section 6.3.2.

7.2.2.3 Application Curves

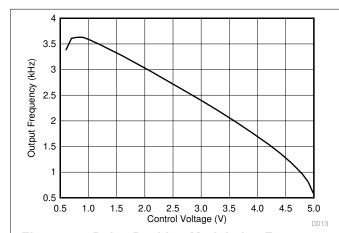


Figure 7-4. Pulse-Position-Modulation Frequency vs Control Voltage, V_{CC} = 5V

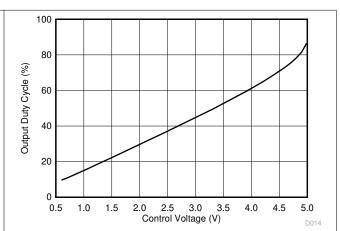


Figure 7-5. Pulse-Position-Modulation Duty Cycle vs Control Voltage, $V_{CC} = 5V$



8 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

8.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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8.3 Trademarks

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8.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision H (December 2024) to Revision I (March 2025)	Page
•	Updated Device Information table to show correct temperature range for each device	1
•	Added thermal specifications for DB package in Thermal Information	3
•	Changed minimum monostable pulse duration from 1µs to 10µs in Monostable Operation to fix typo	8



10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
JM38510/10902BCA	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	JM38510 /10902BCA	Samples
NA556D	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-40 to 105	NA556	
NA556DR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 105	NA556	Samples
NA556N	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 105	NA556N	Samples
NE556D	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	0 to 70	NE556	
NE556DBR	ACTIVE	SSOP	DB	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	N556	Samples
NE556DR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	NE556	Samples
NE556N	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	NE556N	Samples
NE556NSR	ACTIVE	SOP	NS	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	NE556	Samples
SA556N	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SA556N	Samples
SE556J	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	SE556J	Samples
SE556JB	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	SE556JB	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.



PACKAGE OPTION ADDENDUM

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- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
NA556DR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
NE556DBR	SSOP	DB	14	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
NE556DR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
NE556NSR	SOP	NS	14	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1



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*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
NA556DR	SOIC	D	14	2500	356.0	356.0	35.0
NE556DBR	SSOP	DB	14	2000	356.0	356.0	35.0
NE556DR	SOIC	D	14	2500	356.0	356.0	35.0
NE556NSR	SOP	NS	14	2000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
NA556N	N	PDIP	14	25	506	13.97	11230	4.32
NA556N	N	PDIP	14	25	506	13.97	11230	4.32
NE556N	N	PDIP	14	25	506	13.97	11230	4.32
NE556N	N	PDIP	14	25	506	13.97	11230	4.32
SA556N	N	PDIP	14	25	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-150.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



NOTES:

- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
 Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
 Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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